

Notice of References Cited

Application/Control No.

10/786,795

Applicant(s)/Patent Under
Reexamination
VANGHI ET AL.

Examiner

SHANTELL HEIBER

Art Unit

2617

Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0016493	08-2001	KIM et al.	455/436
	B	US-			
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	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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